# PROTON

## JSC "Proton"

## Photodiode array chip FM056P

## **Description**

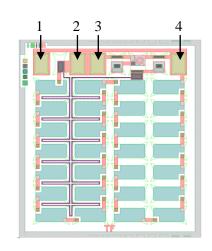
FM056P is designed to drive MOSFETs, including SiC MOSFETs, with threshold voltage 3-7 V and can be used in MOS-relay within one package or as a separate device. The spectral response range is 850 – 940 nm. The chip should be used for face-to-face coupling design together with one IR-LED.

#### **Features**

- Contact pad's material Aluminium
- Contact pad's size 0.09 x 0.13 mm
- Module size 1.2 x 1.4 mm (including scribe line)
- Scribe line width 80 μm
- Chip thickness  $0.32 \text{ mm} \pm 0.02 \text{ mm}$

### **Absolute maximum ratings**

Storage Temperature	-65°C to 150°C
Operating Junction Temperature	-55°C to 125°C



- 1- Output
- 2 GND
- 3 GND
- 4 Output

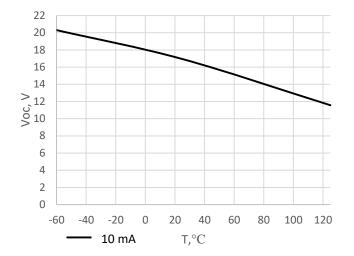
## Electrical characteristics (T = 25 °C)

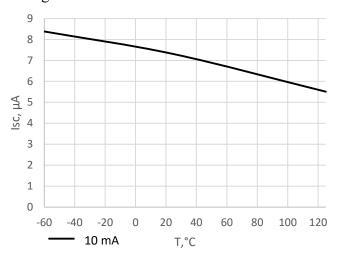
Parameter	Symbol	Unit	Min.	Тур.	Max.	Condition
Open Circuit Voltage	V <sub>OC</sub>	V	14.0	15.5	-	1
Open Circuit Voltage	V <sub>OC</sub>	V	-	17.0	-	2
Short Circuit Current	$I_{SC}$	μΑ	2.0	2.2	-	1
Short Circuit Current	$I_{SC}$	μΑ	-	7.3		2
Output Voltage	Vo	V	-	-	0.9	3
Turn-On Time	T <sub>ON</sub>	ms	_	0.4	1.0	4
Turn-Off Time	$T_{OFF}$	ms	-	0.05	0.3	4

- 1 Light source with peak wavelength  $\lambda = 850 \pm 20$  nm that provides surface irradiance  $E = 20 \text{ mW/cm}^2$  is used.
- 2 Testing condition:  $I_F$  = 10 mA. The PDA is assembled with IR-LED of P = 1500  $\mu$ W (at 10 mA) with peak wavelength  $\lambda$  = 850  $\pm$ 20 nm.
- $3 No light. I_o=100 \mu A$
- 4- Typical value at  $I_F=10$  mA,  $C_L=330$  pF. The PDA is assembled with IR-LED of  $P=1500~\mu W$  (at 10 mA) with peak wavelength  $\lambda=850\pm20$  nm. The measurement was performed in accordance with the specified testing circuit and diagram.

## **Typical characteristics**

Typical characteristics` measurement is performed on PDA chip assembled with IR-LED chip of  $P=1500~\mu W$  (at 10~mA) with peak wavelength  $\lambda=850~\pm20~nm$ .





Picture 1 – typical characteristics  $V_{OC}$  (T)

Picture 2 – typical characteristics I<sub>SC</sub> (T)

## Dynamic parameters testing circuit and diagram

